



NanoLab Delivers!

'Nano-Tools'

Tools to
Measure / Analyze
Your Materials

**Analytical Services
On Demand**

Our Commitment to You

Nanolab is committed to your needs and shows that commitment by the un-ending, yearly acquisition of State-of-the-Art instrumentation for:

- Materials Characterization
- Problem Solving
- Failure Analysis
- Production Control, and
- Quality Control

Nanolab Technologies offers cutting edge technology and expertise for Failure Analysis, Analytical Microscopy, Surface Analysis and FIB circuit edit. An experienced team of engineers and scientists using state-of-the-art equipment equals guaranteed accuracy and results.

Nanolab is very pleased to offer both the expertise and technology to provide solutions and answers to the ever increasing challenges that our customers experience with today's shrinking geometries.

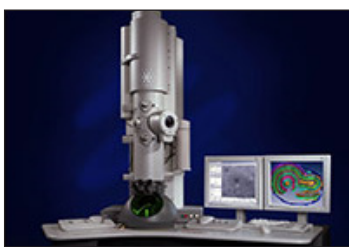
Thermo K-Alpha 'XPS' System



CIRCUIT TESTING & ANALYSIS TOOLS

- 3D X-Ray Microscopy
- Automated Testing Equipment
- Emission Microscopy (EMMI)
- Real Time X-ray Analysis

FEI Tecnai STEM System - 300 kV; EELS; EDS



Dage '2D and 3D X-ray Microscope'

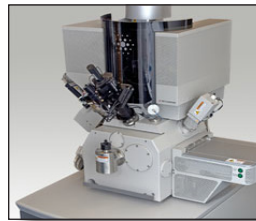


IMAGING TOOLS

- 3D X-Ray Microscopy
- Backscattered Electron Microscopy
- Dual-Beam FIB-SEM Microscopy
- Scanning Acoustic Microscopy
- Scanning Electron Microscopy

State-Of-The-Art Instrumentation

FEI Helios NanoLab 450 Dual Beam UHR FIB-SEM



*You bring the samples,
We provide the results you need.*

CHEMICAL ANALYSIS TOOLS

- Electron Energy Loss Spectroscopy
- Energy Dispersive Spectroscopy - X-rays
- X-ray Photoelectron Spectroscopy

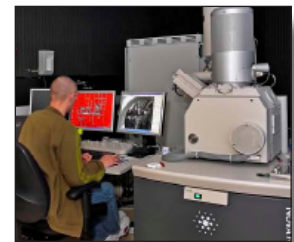
Committed to Quality & Customer Service

NanoLab Technologies, 1708 McCarthy Blvd., Milpitas,
California 95035 USA **Website:** www.nanolab1.com
E-mail: sales@nanolab1.com, **Sales Tel:** 1.408.433.3320

Your Personalized NanoLab Tool-Kit Includes:

- Imaging & Sizing
- Chemical Analysis
- Circuit Testing
- Disassembly
- Nanolab People

FEI 630 Nova NanoSEM Microscope



DISASSEMBLY TOOLS

- Decapping
- Deprocessing
- Die removal
- Precision ion polishing
- Cross-sectioning
- Wet chemical etching

300 mm XPS System - Thermo



SIZING TOOLS

- High Resolution Digital Microscopy
- Scanning Transmission Electron Microscopy
- Transmission Electron Microscopy

Free consultation by phone.

Work On-Site with us.



NanoLab Delivers!

NanoLab Services Flyers List

- Strengths & advantages
- Data & images produced
- Routine analyses
- Advanced analyses
- Global uses
- Applications
- Image details
- Spectra & plot features
- Sample treatments
- Sample preparation
- Typical analysis times
- Higher data quality choices
- Specialty work & data
- Limits of tool & technique
- Special aspects of techniques
- Merits of each instrument

Got A Question! Let's Talk. Give Us A Call.

FEI V600 'FIB' Ion Milling System



SemiCaps SOM 4000



CONTENT OF YOUR REPORT

- Summary Of Results - Useful Information
- All Images, Spectra & Plots (Processed)
- Image(s) Of Samples Before Prep
- Elemental Composition Table(s)*
- Chemical State Assignments*
- Data In ASCII, JPEG Or Other Formats
- Analysis Strategy Agreed On
- Description Of Samples
- History Of Samples
- Description Of The Analysis
- Reference Data As Needed
- Suggestions For Next Steps

*From Tools Producing Spectroscopic Data

NANOLAB'S ADVANTAGES

- State-of-the-art instrumentation
- Free consulting
- Free pick-up & delivery
- On-site collaboration
- Reliability
- Transparent business practices
- Detailed reports
- Experienced scientists & engineers
- Turnaround time
- Optional data quality levels
- User site training seminars

Call us - We're here to help!

Hitachi FS200 'Scanning Acoustic Microscope'



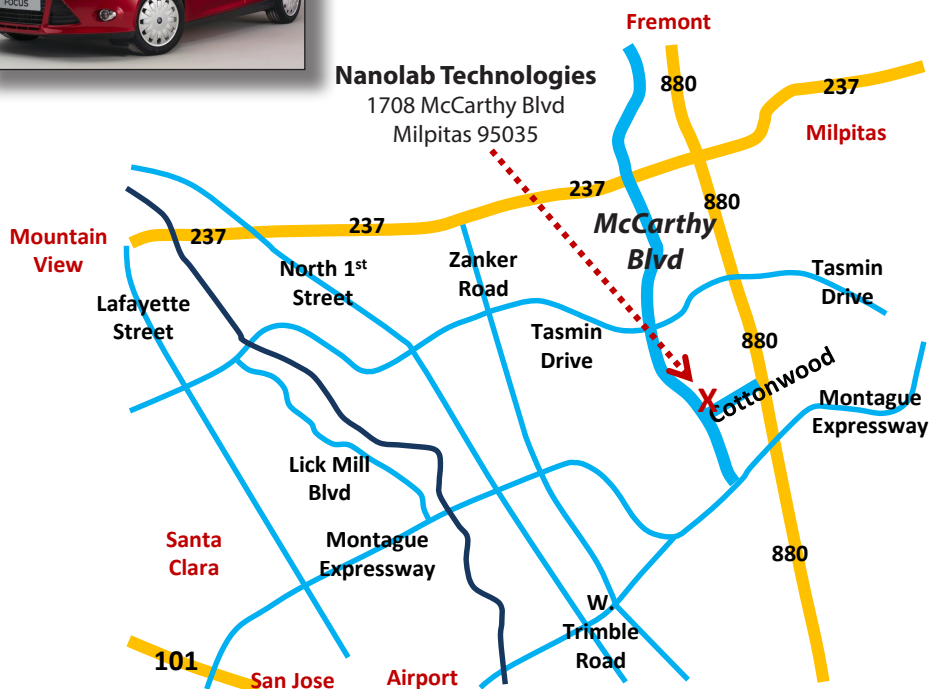
Nanolab On Wheels - Courtesy Sample Pickup



Polishing & Cross-Sectioning



FEI Alura 855 Dual Beam FIB-SEM



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